

Notice of References Cited

Application/Control No.

10/786,554

Applicant(s)/Patent Under
Reexamination
TAKEHARA, SHINTARO

Examiner

HENOK G. HEYI

Art Unit

2627

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,808,979 A	09-1998	Ishibashi et al.	369/44.35
*	B	US-2001/0053115 A1	12-2001	Nobukuni et al.	369/59.12
*	C	US-2002/0126593 A1	09-2002	Okumura et al.	369/47.5
*	D	US-7,102,967 B1	09-2006	Ma et al.	369/44.25
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.